

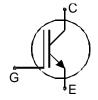
IGBT Chip in Fieldstop-technology

FEATURES:

- 1200V Fieldstop technology 120µm chip
- low turn-off losses
- short tail current
- positive temperature coefficient
- integrated gate resistor

This chip is used for:

IGBT Modules



Applications:

SMPS, resonant applications

Chip Type	V _{CE}	I _{Cn}	Die Size	Package	Ordering Code
SIGC156T120R2CQ	1200V	100A	12.59 X 12.59 mm ²	sawn on foil	SP0000-83655

MECHANICAL PARAMETER:

Raster size	12.59 X 12.59	mm ²		
Emitter pad size	8 x (3.98 x 2.38)			
Gate pad size	1.46 x 0.8			
Area total / active	158.5 / 132.6			
Thickness	120	μm		
Wafer size	150	mm		
Flat position	90	grd		
Max.possible chips per wafer	82 pcs			
Passivation frontside	Photoimide			
Emitter metallization	3200 nm Al Si Cu			
Collector metallization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding			
Die bond	electrically conductive glue or solder			
Wire bond	Al, <500μm			
Reject Ink Dot Size	Ø 0.65mm ; max 1.2mm			
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C			



MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit
Collector-emitter voltage, T _j =25 °C	V _{CE}	1200	V
DC collector current, limited by T _{jmax}	I _C	1)	А
Pulsed collector current, t _p limited by T _{jmax}	I _{cpuls}	300	А
Gate emitter voltage	V _{GE}	±20	V
Operating junction and storage temperature	T_j , T_{stg}	-40 + 150	°C

¹⁾ depending on thermal properties of assembly

STATIC CHARACTERISTICS (tested on chip), T_j =25 °C, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
Turumeter	Cymbol	Conditions	Min.	typ.	max.	
Collector-emitter breakdown voltage	V _{(BR)CES}	V_{GE} =0V , I_{C} =5mA	1200			
Collector-emitter saturation voltage	V _{CE(sat)}	V _{GE} =15V, I _C =100A		2.1		V
Gate-emitter threshold voltage	V _{GE(th)}	I _C =4mA , V _{GE} =V _{CE}		5.5		
Zero gate voltage collector current	I _{CES}	V _{CE} =1200V , V _{GE} =0V			12	μA
Gate-emitter leakage current	I _{GES}	V _{CE} =0V , V _{GE} =20V			600	nA
Integrated gate resistor	R _{Gint}			5	7	Ω

ELECTRICAL CHARACTERISTICS (tested at component):

Parameter	Symbol	Symbol Conditions		Value		
raiailletei	Symbol	Conditions	min.	typ.	max.	Unit
Input capacitance	Ciss	V _{CE} =25V,		7850		pF
Output capacitance	Coss	$V_{GE}=0V$,		650		
Reverse transfer capacitance	Crss	f=1MHz		275		

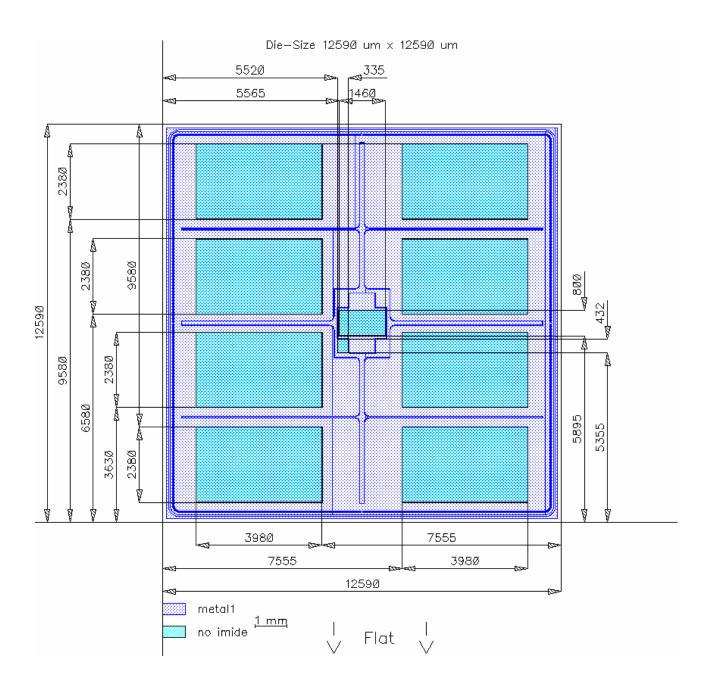
SWITCHING CHARACTERISTICS (tested at component), Inductive Load

Parameter	Symbol	Conditions 1)	Value			Unit
	Symbol	Conditions	min.	typ.	max.	
Turn-on delay time	$t_{d(on)}$	T _j =125°C		234		ns
Rise time	t _r	$V_{\rm CC} = 600 \text{V},$		40		
Turn-off delay time	$t_{d(off)}$	I _C =100A, V _{GE} =-15/15V,		367		
Fall time	t_{f}	$R_{\rm Gext}$ = 5.6 Ω		84		

 $^{^{1)}}$ values also influenced by parasitic L- and C- in measurement and package.



CHIP DRAWING:





FURTHER ELECTRICAL CHARACTERISTICS:					
This chip data sheet refers to the device data sheet					
DESCRIPTION:					
AQL 0,65 for visual inspection according to failure catalog					
Electrostatic Discharge Sensitive Device according to MIL-STD 883					
Test-Normen Villach/Prüffeld					

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